	RECIPIENT
SPECIFICATIONS	
Model: FC-135	
32.768kHz	_
Spec. No.: 9pF+/-20ppm	_
Date: Nov. 25th, 2005	
Date: 11011 2000	_
EDCON Tairren Taalmalaar, & Trad	ina I 4d
EPSON Taiwan Technology & Trad	ing Lia.
14F, No.7, Song Ren Road, Taipei 110 Taiwan,	ROC.
Phone: +886 2-8786-6688	
Fax: +886 2-8786-6660	

SPECIFICATIONS

1. Application

This document is applicable to the crystal resonators that are delivered to **customer** from EPSON TOYOCOM Corp.

This product is not authorized for use as critical components in life support device or systems.

2. Production code

This crystal resonator's production code is FC-135.

3. Packing

It is subject to the packing standard of EPSON TOYOCOM Corp.

4. Warranty

Defective parts which originate with us are replaced free of charge in the case of defects being found with 12 months after delivery.

5. Amendment and/or termination

Amendment and/or termination of this specification is subject to the agreement between the two parties.

6. Contents

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Level <1.0uW is also acceptable.

[1] Absolute maximum ratings

L 1 1 1 1050 late maxima ratings			
Item	Symbol	Rating value	
Storage temperature	Tstg	-55°C to +125°C	
Maximum drive level	DL	1.0 μW	

[2] Operating range

		Value		
Item	Symbol	Min.	Тур.	Max.
Operating temperature range	Topr	-40°C		+85°C
Drive level	DL	0.01 μW	0.1 μW	0.5μW
Vibration mode			Fundamental	

Item	Symbol	Value	→external capacitor=9p Use CL=9pF
Frequency	f_1	32.768 kHz	→ external capacitor=12
Frequency tolerance	Δ f/f	± 20 ×10 ⁻⁶	CL = 9 pF Max: <=9pF Ta = +25± 3°C, Drive level : 0.1 μW Not include aging
Series resistance	Rı	70 kΩ Max. Ma	x: <80K
Motional capacitance	C1	Typ. 3.4 fF	CI meter : Saunders 140B Drive level : 0.5 μW
Shunt capacitance	C0	Тур. 1.2 рF М	ax: <2pF
Turnover temperature	θТ	+25 ± 5 °C	Values are calculated by the frequencies at +10, +25, +40°C with C-MOS circuit.
Temperature coefficient	a	-4.0×10^{-8} /° C^2 Max.	
Isolation resistance	IR	500 MΩ Min.	DC 100V, 60 seconds Between terminal #1 and terminal #2
Aging	fa	$\pm 3 \times 10^{-6}$ / year	Ta = +25 °C ± 3 °C Drive level : 0.1 μW

[4] Environmental and Mechanical characteristics

[4]	Environmental and Mechanical characteristics				
No.	Items	Value	Conditions		
			100g dummy(SEIKO EPSON Standard), Free drop from		
1	Shock resistance	* $\Delta f/f : \pm 8 \times 10^{-6}$	1500 mm height on to the concrete.		
			3 directions \times 10 cycles *2		
			10 ~ 500 Hz 1.5mm p-p or 10G		
2	Vibration resistance	* Δ f/f : \pm 3 ×10 ⁻⁶	$10 \text{ Hz} \rightarrow 500 \text{ Hz} \rightarrow 10 \text{ Hz} : 15 \text{ min./cycle}$		
			Log. Sweep 6 h (2 hours × 3 directions) *2		
			Testing Process		
			1) Leave in $+85\pm2^{\circ}\text{C}\times85\pm5\%\text{RH}\times24\pm1\text{Hrs}$		
3	Soldering heat resistance	$\Delta f/f: \pm 5 \times 10^{-6}$	2) Measure (Reference data) 24 hours later at leaving in room temperature after item 1) treatment		
3	Soldering near resistance	Δ 1/1 . ± 3 ×10	3) Treat the Reflow 2 times by the following profile in the next page		
			4) Measure the data at 1 hour and 24 hours after the item 3) treatment		
4	High temperature storage	* $\Delta f/f$: ± 10×10 ⁻⁶	+125 °C × 1000 hours *1		
4	riigii temperature storage	* $\Delta f/f : \pm 7 \times 10^{-6}$	+85 °C× 1000 hours *1		
5	Low temperature storage	* Δ f/f : ± 10 ×10 ⁻⁶	-55 °C× 1000 hours *1		
6	High temperature and humidity storage	* Δ f/f : ± 10 ×10 ⁻⁶	+85 °C × 85 %RH × 1000 hours *1		
	Temperature cycle	* $\Delta f/f : \pm 10 \times 10^{-6}$	-55 °C ↔ +125 °C		
7	Temperature cycle	·Δ 1/1 . ± 10 ×10	30 minutes at each temperature × 100 cycles *1		
8	Aging	* $\Delta f/f$: $\pm 3 \times 10^{-6}$	+25± 3 °C× 1 year (No-bias)		
	7.55	* $\Delta f/f$: $\pm 3 \times 10^{-6}$	+25± 3 °C× 1 year(Bias by SEIKO EPSON STD circuit)		
9	Sealing	$1 \times 10^{-8} \text{ hPa} \cdot 1 / \text{ s Max.}$	For He leak detector		
10	Shear	No peeling-off at a soldered part	10 N press for 10 ± 1 s. Ref. IEC 60068-2-21		
11	Pull - off	No peeling-off at a soldered part	10 N press for 10 ± 1 s. Ref. IEC 60068-2-21		
12	Substrate bending	No peeling-off at a soldered part	Bend width reaches 3 mm and hold for $5 \text{ s} \pm 1 \text{ s} \times 1 \text{ time}$ Ref. IEC 60068-2-21		
13	Solvent resistance	The marking shall be legible	Ref. JIS C 0052 or IEC 60068-2-45		

< Notes >

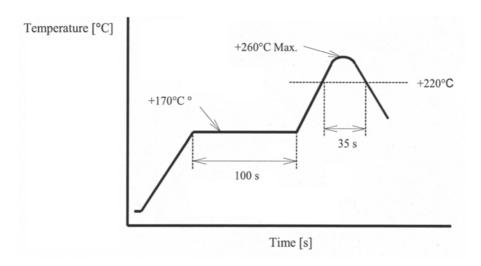
- 1. *1 Each test done independently.
- 2. *2 Measuring 2 h to 24 h later leaving in room temperature after each test. Drive level : 0.5 μW
- 3. *3 Pre conditionings (Treat the Reflow 2 times with the following profile) Initial value shall be after 24 h at room temperature.

Shift of series resistance at before and after the test should be less than ± 20 % or less than $\pm 15 k\Omega$.

In case high temperature storage ($\pm 125^{\circ}\text{C} \times 1~000~\text{h}$), Soldering heat resistance, shift of series resistance at before and after the test should be less than $\pm 30~\%$ or $\pm 20~\text{k}\Omega$.

♦ Infrared-reflow

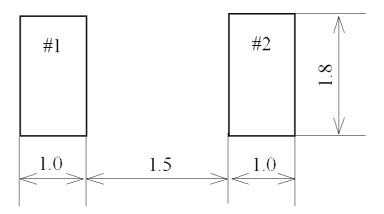
Pre heating temperature $: +170 \, [^{\circ}C]$ Pre heating time $: 100 \, [s]$ Heating temperature $: +220 \, [^{\circ}C]$ Heating time $: 30 \, [s]$



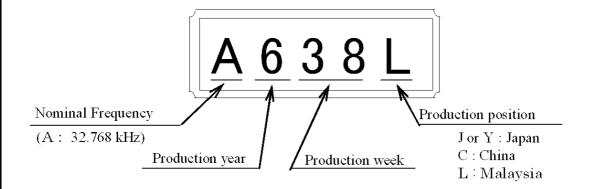
5] Dimensions and Marking layout 1.Dimensions ±0.10 ± 0.10 0.80 3.20 ϕ 0.55 (N.C) C0.2 #2 #1 0.1 ±0.10 **→** 0.65 → 1.70 Package : Ceramic(Al₂O₃) Terminal Au plate : 0.5 μ m Min. Lid: Glass2.Internal Connection #1 #2 FC-135 Type Terminal treatment Solder plate Unit 1 = 1 mm

3. Recommended soldering pattern

Unit: 1 = 1 mm



4. Marking layout



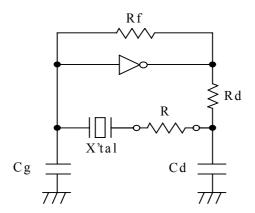
* The above marking layout shows only marking contents and their approximate position and it is not for font, size and exact position.

Туре	FC-135	Unit	1=1 mm

[6] Notes

- 1. Max two (2) times reflow is allowed. Once miss soldering is happened, hand work soldering by soldering iron is recommended. $(+350^{\circ}\text{C} \times \text{within } 5 \text{ s})$
- 2. Patterning should be followed by our recommended one.
- 3. Applying excessive excitation force to the crystal resonator may cause deterioration damage.
- 4. Unless adequate negative resistance is allocated in the oscillation circuit, start up time of oscillation may be increased, or no oscillation may occur.

How to check the negative resistance.



- (1) Connect the resistance (R) to the circuit in series with the crystal resonator.
- (2) Adjust R so that oscillation can start (or stop).
- (3) Measure R when oscillation just start (or stop) in above (2).
- (4) Get the negative resistance

$$-R = R + CI$$
 value.

(5) Recommended -R

$$|-R| > CI \times (5 \sim 10)$$

- 5. The shortest patterning line on board is recommendable.

 Too long line on board may cause of abnormal oscillation.
- 6. To avoid mull function, no pattern under or near the crystal is allowed. Solder paste should be more than 150 μ m thickness.
- 7. This device must be stored at the normal temperature and humidity conditions before mounting on a board.
- 8. Too much exciting shock or vibration may cause deterioration on damage.
 Depending on the condition such as a shock in assembly machinery, the products may be damaged.
 Please check your condition in advance to maintain shock level to be smallest.
- 9. Depending on the conditions, ultrasonic cleaning may cause resonant damage of the internal crystal resonator. Since we are unable to determine the conditions (type of cleaning unit, power, time, conditions inside the bath, etc.) to be used in your company, we cannot guarantee the safety of this unit when it is cleaned in an ultrasonic cleaner.
- 10. Ink marking may be damaged by some kind of solvent, please take precautions when choosing solvent by your selves.
- 11. Please refer to packing specification regarding how to storage the products in the pack.

EPSON

SEIKO EPSON Quartz Device Div.

RELIABILITY TEST DATA Product Name: FC-135

Date of Issue Sep. 15. 200 4

Signature

T. Yanagisawa

The Company evaluation condition

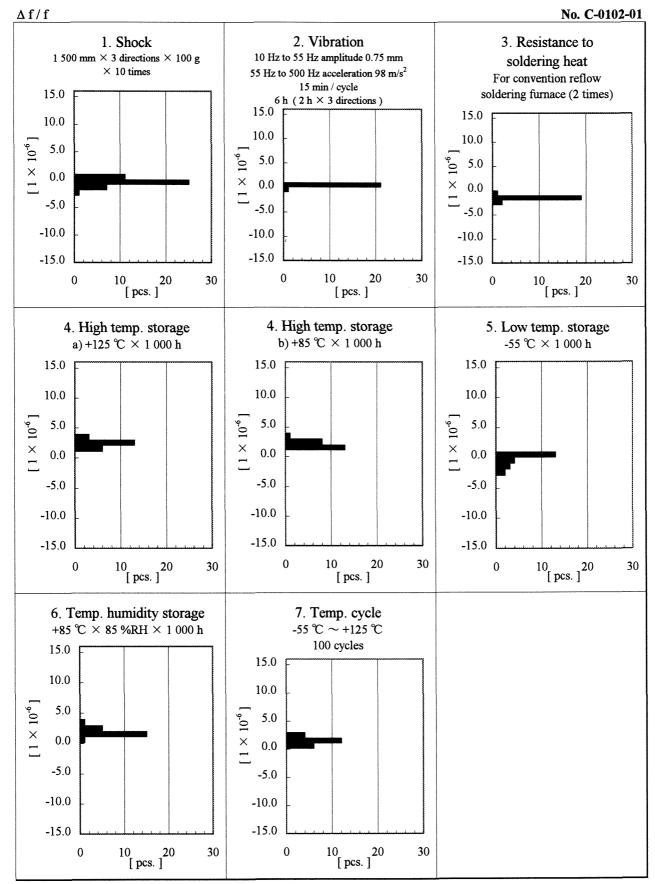
We o	evaluate environmenta	and mechanical characteristics by the following		No. C-0.	
			VALUE *1 *2	TEST	I
No.	ITEM	TEST CONDITIONS	$\Delta f/f$	Qty	Qty
			$[1 \times 10^{-6}]$	[n]	[n]
	O: 1	100 g dummy (SEIKO EPSON Standard)			
1	Shock	drop from 1 500 mm height on to the	*3 ± 8	44	0
		concrete 3 directions 10 times			ļ
		10 Hz to 55 Hz amplitude 0.75 mm			
2	Vibration	55 Hz to 500 Hz acceleration 98 m/s ²	*3 ± 3	22	0
		10 Hz ~ 500 Hz ~ 10 Hz 15 min / cycle			
		6 h (2 h × 3 directions)			
	Resistance to	For convention reflow soldering furnace			l
3	soldering heat	(2 times)	± 5	22	0
	High temperature	a) +125°C × 1 000 h	*3 a) ± 10	a) 22	a) (
4	storage				
		b) +85 °C × 1 000 h	*3 b) ± 7	b) 22	b) (
	Low temperature				
5	storage	-55 °C × 1 000 h	*3 ± 10	22	0
	Temperature				
6	humidity storage	+85 °C × 85 %RH × 1 000 h	*3 ± 10	22	0
		 -55 ℃ ~+125 ℃		_	
7	Temperature cycle	30 min at each temp. 100 cycles	*3 ± 10	22	0
_			8-8-		
8	Sealing	For He leak detector	$1 \times 10^{-8} \text{ hPa} \cdot 1/\text{ s Max}.$	11	0
		20 N press for 10 s \pm 1 s	No peeling - off at a		T
9	Shear	Ref. IEC 60068-2-21	solder part	11	Ιo
			,		
		20 N press for 10 s \pm 1 s	No peeling - off at a		
10	Pull - off	Ref. IEC 60068-2-21	solder part	11	0
			•		
		Bend width reaches 3 mm and hold for	No peeling - off at a		
11	Substrate bending	$5 \text{ s} \pm 1 \text{ s} \times 1 \text{ time}$	solder part	11	0
		Ref. IEC 60068-2-21			
12	Solvent resistance	Ref. JIS C 0052 or IEC 60068-2-45	The marking shall be legible	: 11	0

Notes

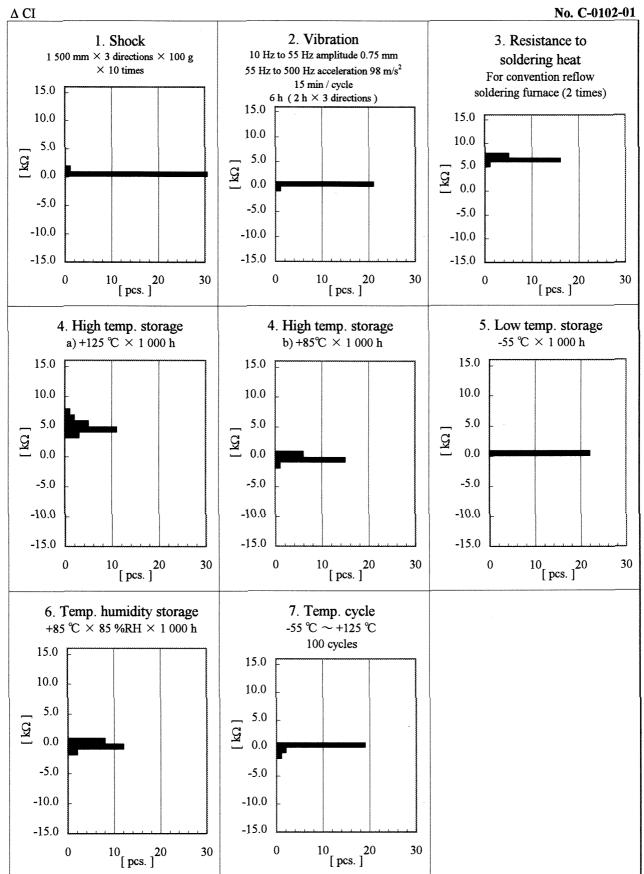
- 1. *1 Each test done independently.
- 2. *2 Measuring 2 h to 24 h later leaving in room temperature after each test. DL: 0.5 $\,\mu W$
- 3. *3 Pre conditionings Initial value shall be after 24 h at room temperature.
- 4. Shift series resistance at before above tests should be less than ± 20 % or less than ± 15 k Ω . In case Resistace to solder heat and High temperature storage (+125 °C × 1 000 h) shift series resistance at before above tests should be less than ± 30 % or less than ± 20 k Ω .

SEIKO EPSON CORP. Quartz Device Div. Quality Assurance Dept.

Product Name: FC-135



Product Name: FC-135



TAPING SPECIFICATION

1. APPLICATION

This document is applicable to FC-13F.

2. CONTENTS

Item No.	Item	Page
[1]	Taping specification	1 to 2
[2]	Inner carton	3
[3]	Shipping carton	
[4]	Marking	4
[5]	Quantity	
[6]	Storage environment	
[7]	Handling	

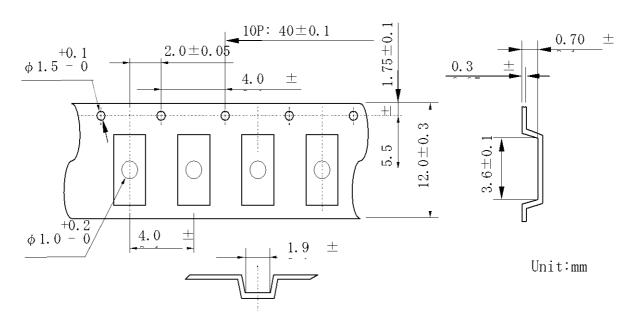
[1] Taping specification

Subject to EIA-481, EIAJ EDX7602, IEC 60286, and JIS C0806.

(1) Tape dimensions

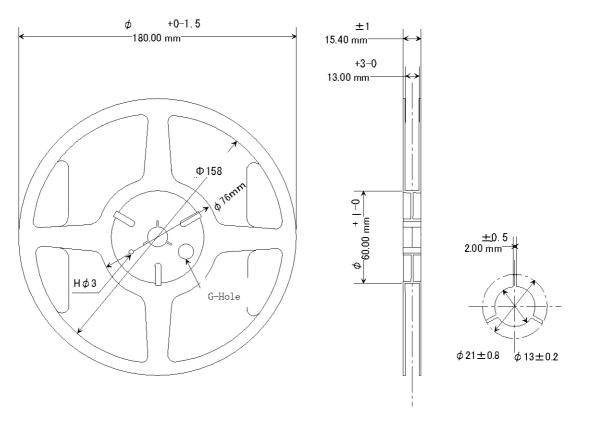
TE1208L Material of the Carrier Tape : PS

Material of the Top Tape : PET+PE



(2) Reel dimensions

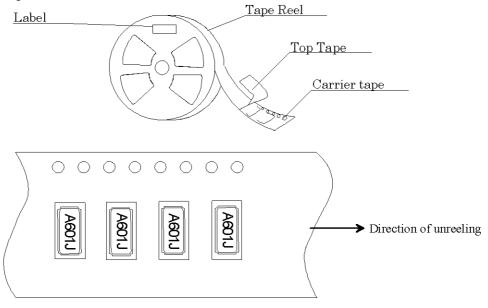
Material of the Reel : PS



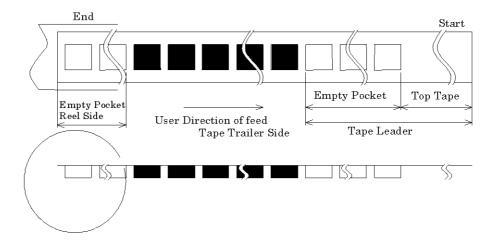
Form and Size of reel window shows are one of the example

(3) Packing

(a) Tape & Reel



(b) Start & End Point



(c) Peel force of the cover tape

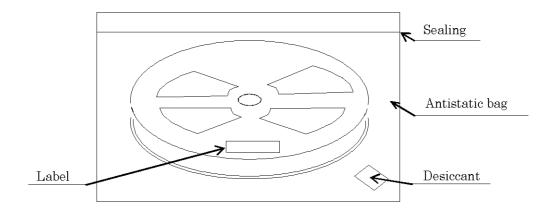
(1) angle : cover tape during peel off and the direction of unreeling shall be 165° to $180^{\circ}.$

(2) peel speed: 5 mm/s.

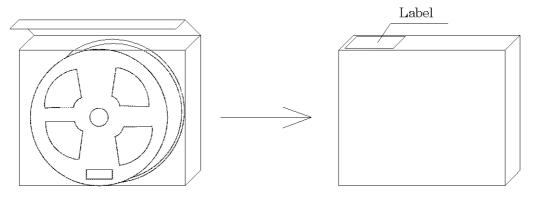
	Empty Space	
Tape Leader	Top Tape	Min. 1 000 mm
	Carrier Tape	Min. 20 pockets
Tape Trailer	Top Tape	Min. 0 mm
Carrier Tape		Min. 20 pockets

[2] Inner Carton

a) Packing to antistatic bag

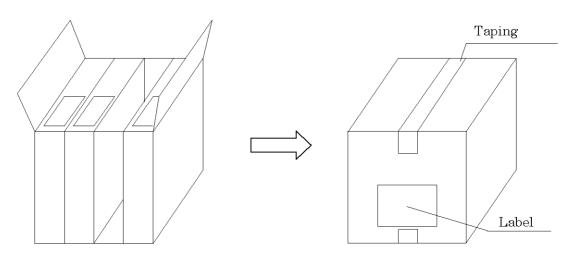


b) Packing to innercarton



[3] Shipping Carton

- Put inner boxes into an outer box.
- If there are room in the outer box,material is put in a shock absorbing together.



[4] Marking

- (1) Reel marking
 - Reel marking shall consist of:
 - 1) Parts name
 - 2) Quantity
 - 3) Manufacturing Date or symbol
 - 4) Manufacturer's Date or symbol
 - 5) Others (if necessary)
- (2) Inner carton marking
 - Same as Reel marking.
- (3) Shipping carton marking
 - Shipping carton marking shall consist of :
 - 1) Parts name
 - 2) Quantity

[5] Quantity

• 5 000 pcs./reel

[6] Storage environment

- (1) To storage the reel at +15 °C to +35 °C, 25 %RH to 85 %RH of Humidity.
- (2) To open the packing just before using.
- (3) Not to expose the sun.
- (4) Not to storage with some erosive chemicals.
- (5) Nothing is allowed to put on the reel or carton to prevent mechanical damage.

[7] Handling

To handle with care to prevent the damage of tape, reel and products.